

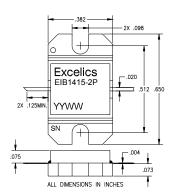
# **EIB1415-2P**

**UPDATED 06/14/06** 

# 14.40-15.35GHz 2W Internally Matched Power FET

### **FEATURES**

- 14.40-15.35 GHz Bandwidth
- Input/Output Impedance Matched to 50 Ohms
- +33.0 dBm Output Power at 1dB Compression
- 7.5 dB Power Gain at 1dB Compression
- 24% Power Added Efficiency
- -46 dBc IM3 at PO = 22.0 dBm SCL
- **Non-Hermetic Metal Flange Package**



## ELECTRICAL CHARACTERISTICS ( $T_a = 25^{\circ}C$ )



#### Caution! ESD sensitive device.

SYMBOL	PARAMETERS/TEST CONDITIONS <sup>1</sup>	MIN	TYP	MAX	UNITS
P <sub>1dB</sub>	Output Power at 1dB Compression $f = 14.40-15.35GHz$ $V_{DS} = 8 \text{ V}, I_{DSQ} \approx 800\text{mA}$	32.0	33.0		dBm
G <sub>1dB</sub>	Gain at 1dB Compression $f = 14.40-15.35GHz$ $V_{DS} = 8 \text{ V}, I_{DSQ} \approx 800\text{mA}$	6.50	7.50		dB
ΔG	Gain Flatness $f = 14.40-15.35GHz$ $V_{DS} = 8 \text{ V}, I_{DSQ} \approx 800\text{mA}$			±0.6	dB
PAE	Power Added Efficiency at 1dB Compression $V_{DS}$ = 8 V, $I_{DSQ} \approx 800$ mA f = 14.40-15.35GHz		24		%
Id <sub>1dB</sub>	Drain Current at 1dB Compression f = 14.40-15.35GHz		850	960	mA
IM3	Output 3rd Order Intermodulation Distortion $\Delta f = 10 \text{ MHz } 2\text{-Tone Test}$ ; Pout = 22.0 dBm S.C.L <sup>2</sup> $V_{DS} = 8 \text{ V}$ , $I_{DSQ} \approx 65\% \text{ IDSS}$ $f = 15.35 \text{GHz}$	-43	-46		dBc
I <sub>DSS</sub>	Saturated Drain Current V <sub>DS</sub> = 3 V, V <sub>GS</sub> = 0 V		1360	1700	mA
$V_P$	Pinch-off Voltage $V_{DS} = 3 \text{ V}, I_{DS} = 12 \text{ mA}$		-2.5	-3.5	V
R <sub>TH</sub>	Thermal Resistance <sup>3</sup>		8.0	9.0	°C/W

#### Note: 1) Tested with 100 Ohm gate resistor.

# MAXIMUM RATINGS AT 25°C

SYMBOLS	PARAMETERS	ABSOLUTE <sup>1</sup>	CONTINUOUS <sup>2</sup>
Vds	Drain-Source Voltage	10V	8V
Vgs	Gate-Source Voltage	-5	-4V
lgsf	Forward Gate Current	21.6mA	7.2mA
lgsr	Reverse Gate Current	-3.6mA	-1.2mA
Pin	Input Power	32.0dBm	@ 3dB Compression
Tch	Channel Temperature	175 °C	175°C
Tstg	Storage Temperature	-65 to +175 °C	-65 to +175 °C
Pt	Total Power Dissipation	16W	16W

Note: 1. Exceeding any of the above ratings may result in permanent damage.

<sup>2)</sup> S.C.L. = Single Carrier Level.

<sup>3)</sup> Overall Rth depends on case mounting.

<sup>2.</sup> Exceeding any of the above ratings may reduce MTTF below design goals.